



MAIL STOP AF
PATENT
8053-1016

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Kazuhiro NAKAJIMA et al.

Conf. 9942

Application No. 10/625,695

Group 2811

Filed July 24, 2003

Examiner Ori Nadav

PRODUCTION PROCESS FOR PRODUCING
SEMICONDUCTOR DEVICES, SEMICONDUCTOR
DEVICES PRODUCED THEREBY, AND TEST
SYSTEM FOR CARRYING OUT YIELD-RATE
TEST IN PRODUCTION OF SUCH
SEMICONDUCTOR DEVICES

AMENDMENT AFTER FINAL REJECTION

Assistant Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

November 3, 2006

Sir:

In response to the Official Action mailed May 9, 2006,
please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing
of claims which begins on page 2 of this paper.

Remarks begin on page 9 of this paper.